Search Notes

Application/Control No	o. Applicant(s)/Paten Reexamination	t under
10/064,467	TSENG ET AL.	
Examiner	Art Unit	
Frank Duong	2616	

SEARCHED				
Class	Subclass	Date	Examiner	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST Search (see printout)	5/15/2006	FD
Inventorship Search (see printout)	5/15/2006	FD
IEEE/Internet Search	5/15/2006	FD